

First investigation of silicon microstrips for the CMS tracker upgrade using edge-TCT

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First measurements of small strip detectors built within the HPK campaign of CMS and characterized using an edge-Transient Current Technique (eTCT) are presented. P and N bulk FZ 320 μm thick detectors are studied and compared to reference Micron detectors. A method to estimate the electric field profile inside the detector using normal incidence TCT and edge-TCT is also presented.

Primary author: FERNANDEZ GARCIA, Marcos (Universidad de Cantabria (ES))

Co-authors: NEUGEBAUER, Hannes (Hamburg University (DE)); GABRYSCH, Markus (CERN); MOLL, Michael (CERN); PACIFICO, Nicola (University of Bergen (NO))

Presenter: FERNANDEZ GARCIA, Marcos (Universidad de Cantabria (ES))

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